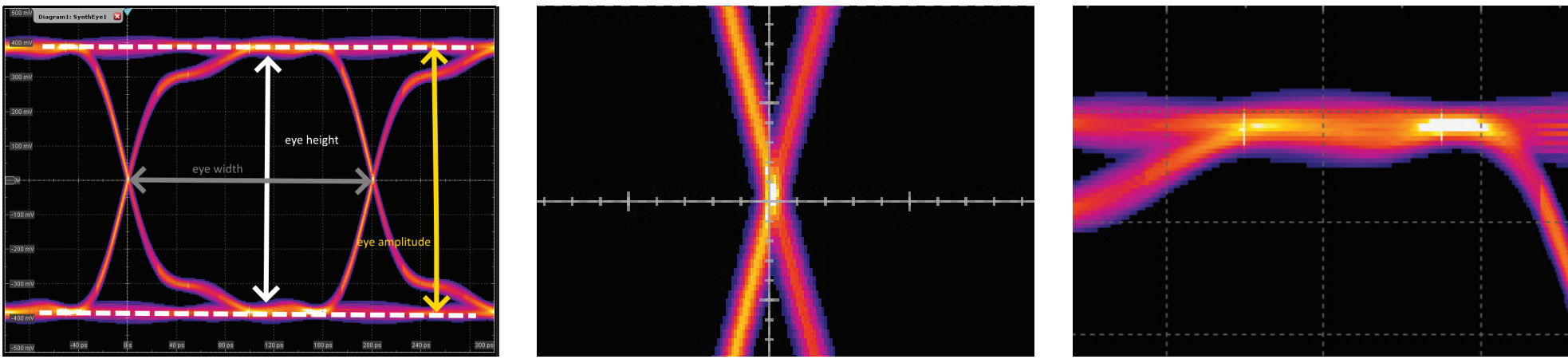


# SIGNAL INTEGRITY EYE TEST

## MEASURING AT THE TRANSMITTER

View the transmitter’s influence on the eye diagram



### PARAMETRIC

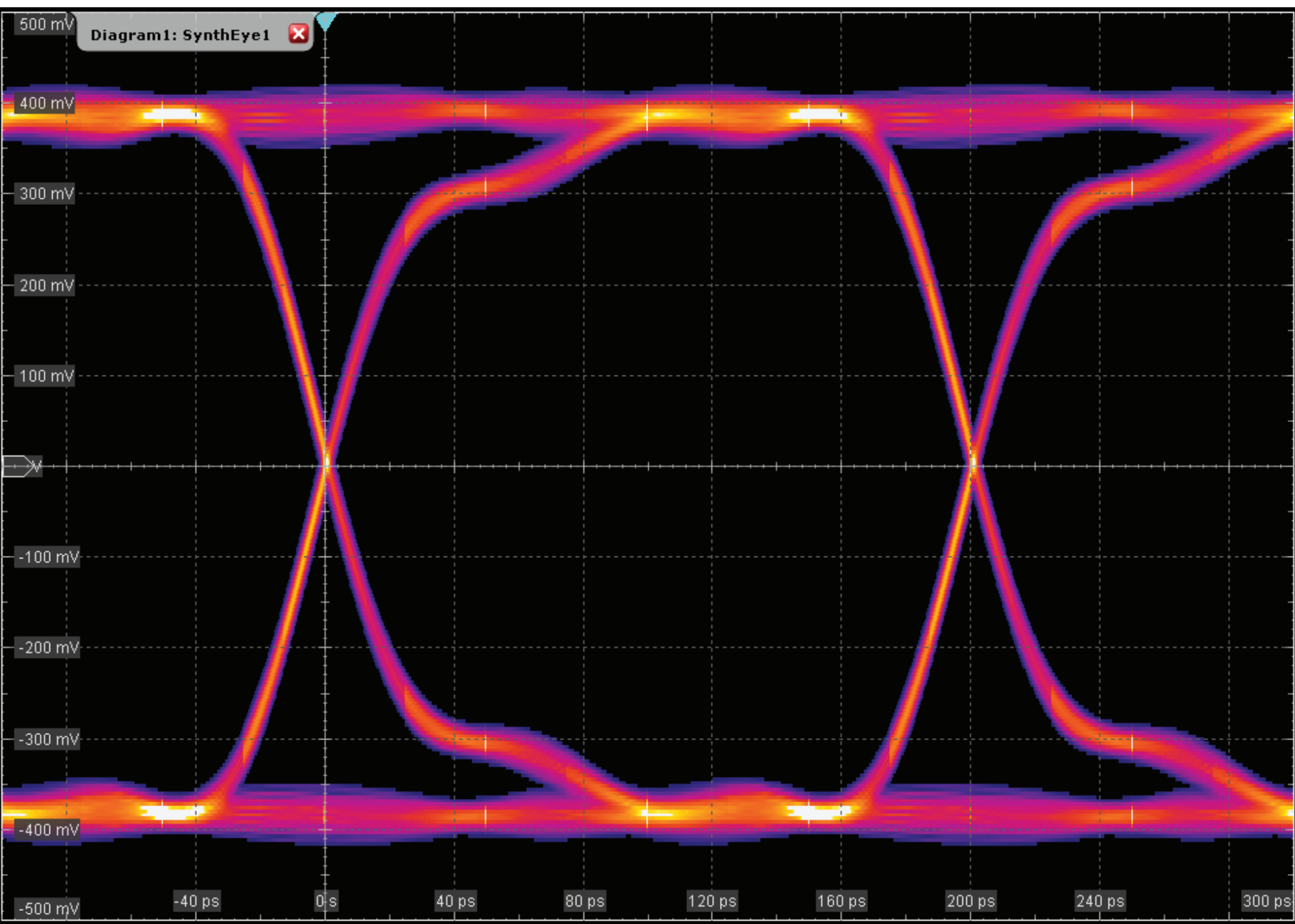
- Transmitter eye opening controlled by amplitude & rise time
- Slew-rate, driver imbalance, intra-pair skew contribute to EMI
- Typical measurements: eye height, eye width, amplitude, rise time, slew rate, mask testing

### JITTER

- Transmitter jitter components include random jitter (RJ) & periodic jitter (PJ)
- RJ is mostly influenced by clock
- PJ mostly influenced by power rail and clock
- Typical measurements: total jitter, random jitter, and deterministic jitter

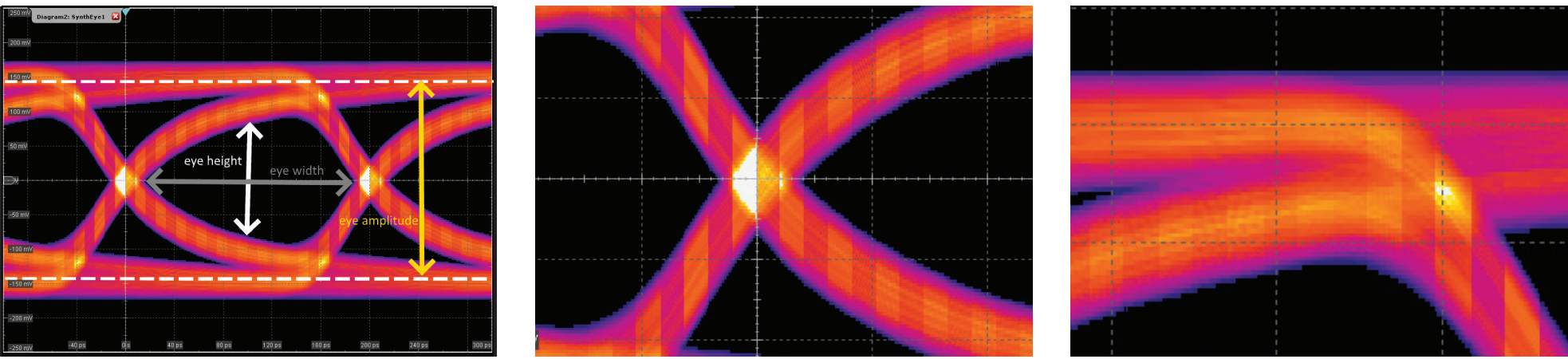
### NOISE

- Observed at the top and bottom of the eye diagram
- Noise at the transmitter is fundamentally power rail noise
- Typical measurements: total noise, random noise, deterministic noise



## MEASURING AT THE RECEIVER

View the system’s influence on the eye diagram



### PARAMETRIC

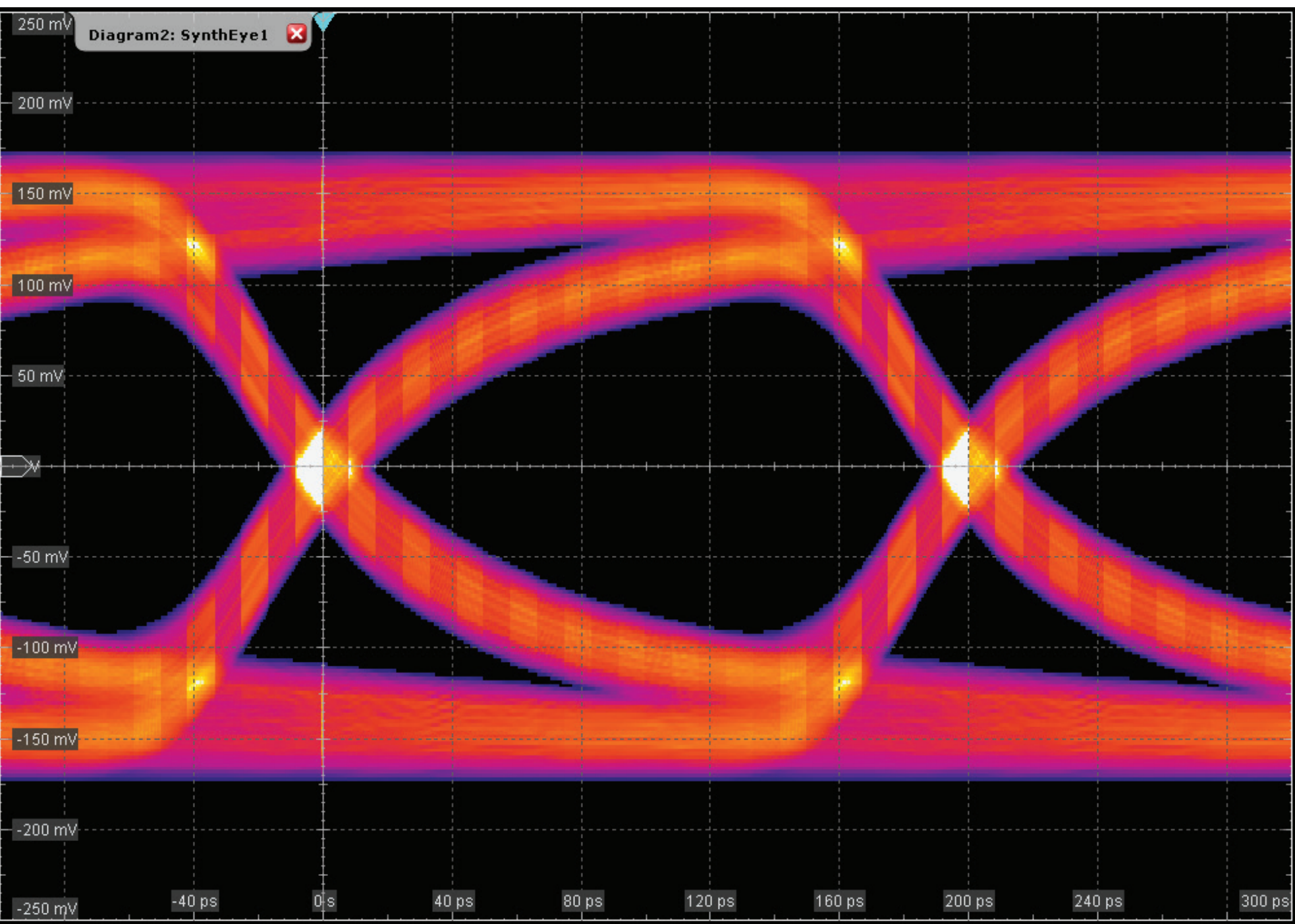
- The channel has frequency dependent losses which reduce the eye height and reduce the eye width
- Typical measurements: eye height, eye width, amplitude, rise time

### JITTER

- The channel’s frequency dependent losses cause data-dependent jitter. Additional jitter sources include crosstalk and EMI
- Typical measurements: data-dependent jitter, total jitter, random jitter, deterministic jitter, and crosstalk

### NOISE / INTERFERENCE

- The channel is susceptible to noise and interference which can be seen at the top and bottom of the eye diagram. The two most common sources of noise and interference are EMI and crosstalk
- Typical measurements: total noise, random noise, deterministic noise, data-dependent noise, EMI FFT analysis

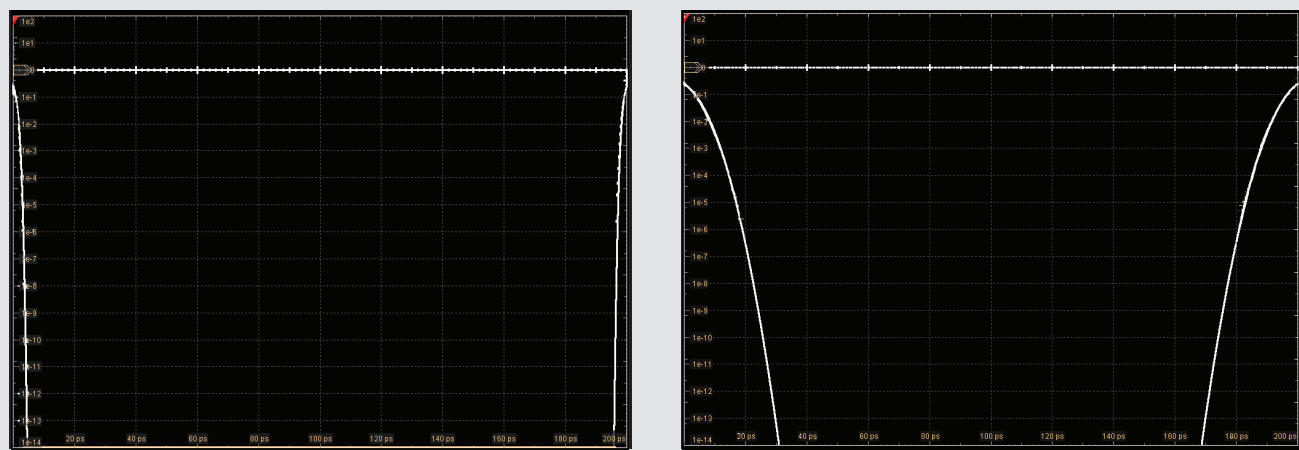


## COMMON CHALLENGES

### AT THE TRANSMITTER

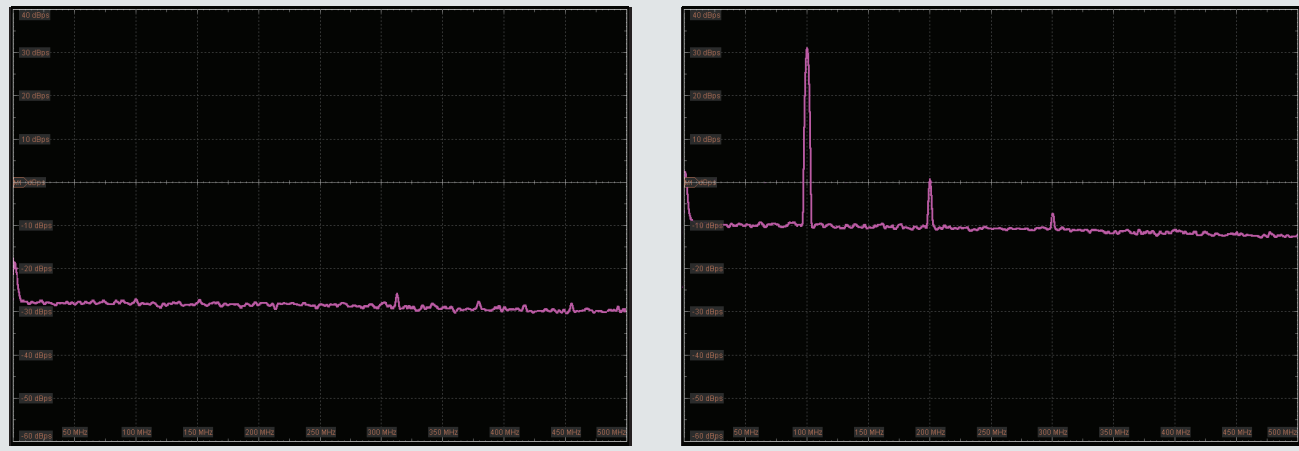
#### RANDOM JITTER

Phase noise can be manifested as RJ of the data signal. The bathtub curve shows the influence of RJ over time



#### PERIODIC JITTER

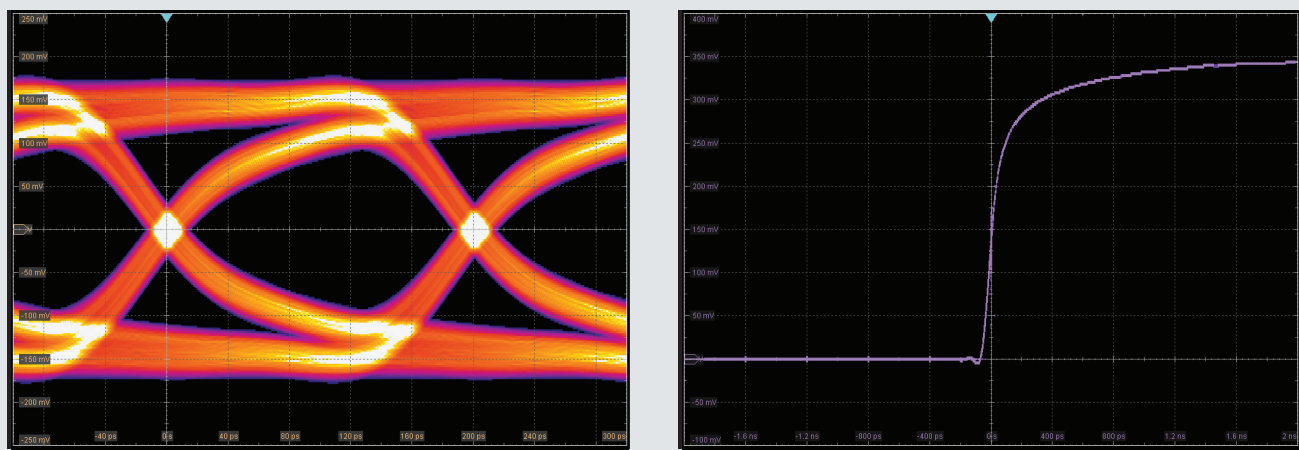
Periodic noise sources such as power supply coupling, can add high amplitude periodic jitter. PJ spectrum helps visualize specific jitter tones



### AT THE RECEIVER

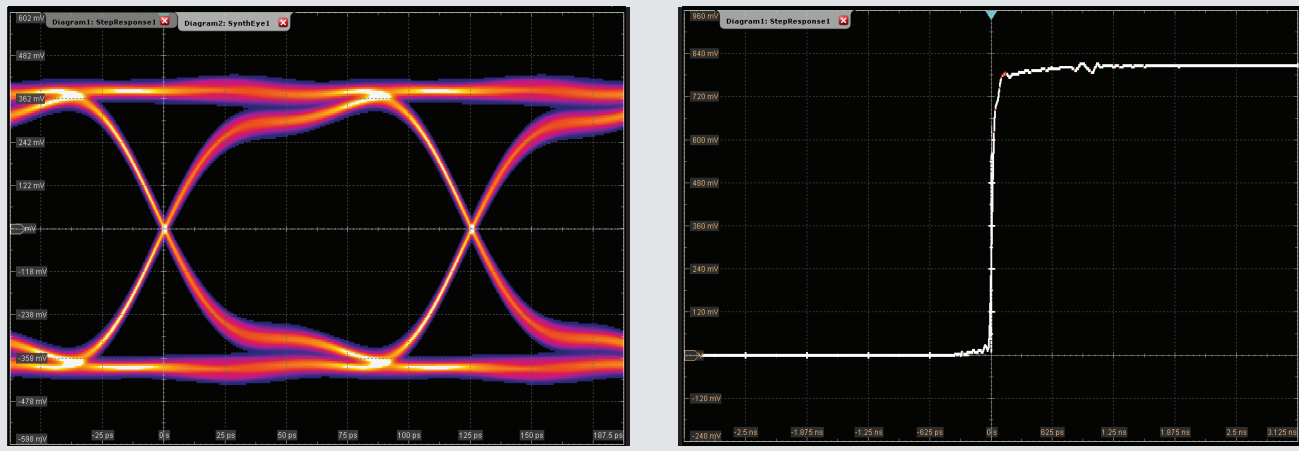
#### LONG CHANNEL

The longer the channel, the higher the signal attenuation due to the dielectric absorption of the channel material



#### REFLECTIONS

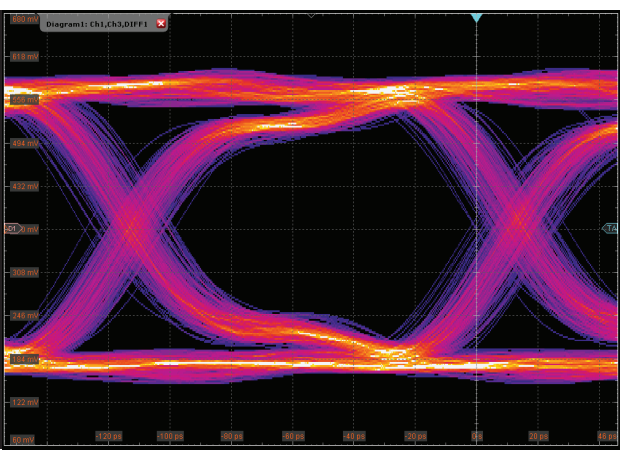
Ringing or overshoot can occur from PCB layout, probing issues or other impedance discontinuities



## HOW TO GENERATE AN EYE DIAGRAM

### ON AN OSCILLOSCOPE

There are three primary ways of capturing an eye diagram. Each of the methods has benefits and trade-offs



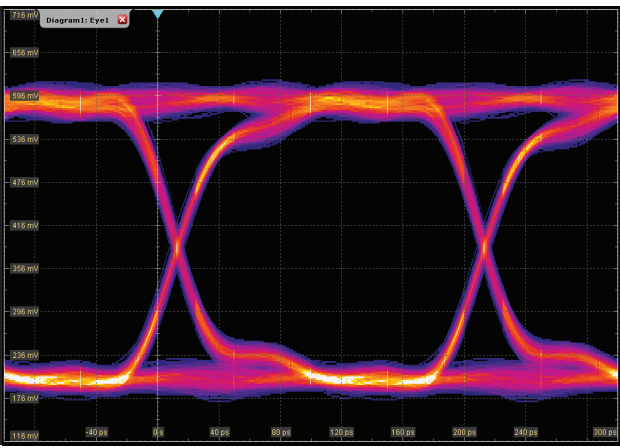
#### TRIGGERED EYE

In this setup there is a system clock used to trigger the oscilloscope. Each acquisition captures one eye diagram and the oscilloscope overlays them

**Benefit:** High UI count, see transient events, simple setup

**Trade-off:** Significant trigger jitter, not consecutive UI, includes time-base wander, live signals only

**Requirement:** Need to have external clock, or alternatively could trigger directly on data with compromised results



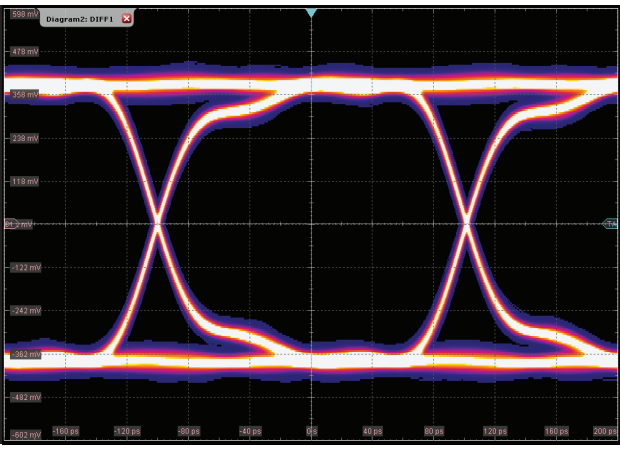
#### DIGITAL CLOCK RECOVERY

Here the clock is embedded in the data signal and is extracted using hardware or software clock recovery. Each acquisition captures one unit interval and the oscilloscope overlays them

**Benefit:** Highest UI count, no trigger jitter, see transient events, enables higher layer protocol triggering

**Trade-off:** Not consecutive UI, live signals only

**Requirement:** Oscilloscope clock data recovery option, minimum pattern duration for PLL lock



#### SINGLE ACQUISITION

A single acquisition is captured and the oscilloscope uses software clock recovery to identify each unit interval and overlay them into an eye diagram

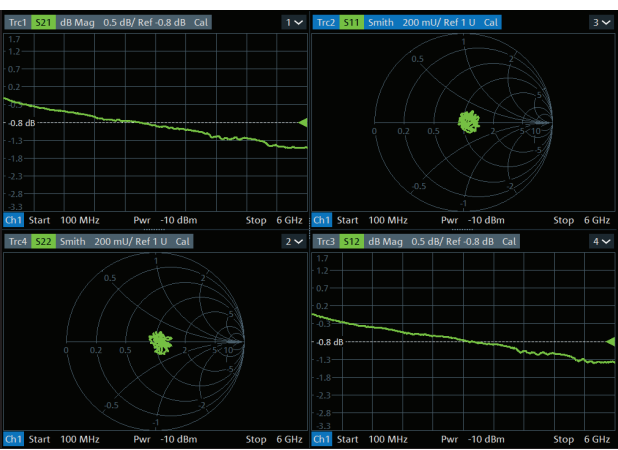
**Benefit:** Consecutive UI, No trigger jitter, off-line processing, facilitates instrument correlations

**Trade-off:** Lowest UI count, no transient events

**Requirement:** Oscilloscope software clock recovery and analysis options

### ON A VECTOR NETWORK ANALYZER

A VNA can translate measured s-parameters into an eye diagram of the channel



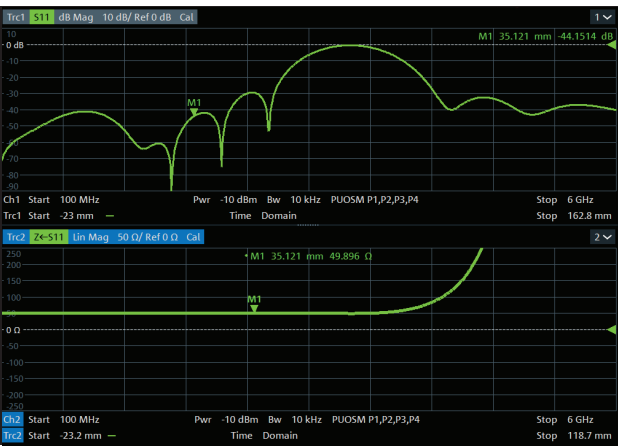
#### MEASURE S-PARAMETERS

In this setup the VNA measures the complete set of s-parameters of the channel

**Benefit:** Insight into channel behavior such as crosstalk or frequency dependent attenuation

**Recommendation:** Measurement accuracy can be improved using de-embedding

**Requirement:** VNA frequency range covers data rate of the channel. Calibration procedure to establish measurement plane at the device under test



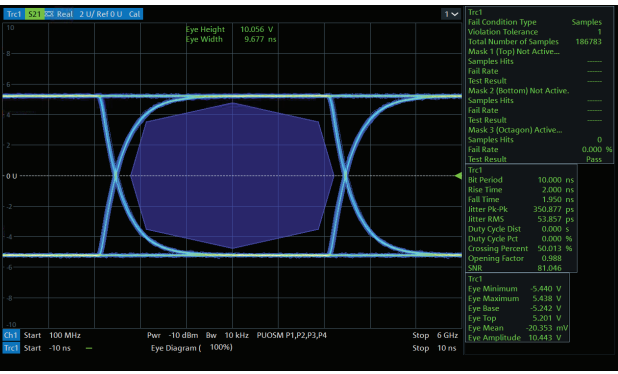
#### CALCULATE TIME DOMAIN

Using an inverse FFT function, modern VNAs generate equivalent time-domain response

**Benefit:** Observe behavior in time-domain (reflections) and measure propagation (group delay)

**Recommendation:** As your channel length goes up, increase the number frequency data points for longer time-domain capture

**Requirement:** VNA time domain option, DC value extrapolated from s-parameters



#### DISPLAY EYE DIAGRAM

Add the time-domain response to a test pattern to simulate an eye diagram

**Benefit:** Evaluate channel performance under varying conditions such as jitter, noise and equalization

**Recommendation:** Add a mask for protocol specific compliance testing

**Requirement:** VNA eye diagram option

## ROHDE & SCHWARZ SIGNAL INTEGRITY SOLUTIONS



### OSCILLOSCOPES

R&S®RTP High-performance Oscilloscope

- High-precision digital trigger without bandwidth limitations
- Real-time de-embedding for triggering and fast acquisition



### VECTOR NETWORK ANALYZERS

R&S®ZNA Vector Network Analyzer

- Signal integrity at a glance with eye diagrams
- Efficient time domain analysis with enhanced resolution



### SIGNAL & SPECTRUM ANALYZERS

R&S®FSW Signal and Spectrum Analyzer

- Detection of extremely short or frequency agile signals
- Flexible analysis tools for easy EMI troubleshooting



### DC POWER SUPPLIES

R&S®NGL200 Power Supply Series

- Fast load regulation with minimal ripple
- Multi-purpose while operating as source and sink



ROHDE & SCHWARZ